See all 18 Products in Family

2" Sphere, General Purpose Integrating Sphere System

General Purpose Integrating Spheres

Stock **#58-584** **6 In Stock**

- 1 + **A$4,040**.00

ADD TO CART

Volume Pricing	
Qty 1-9	**A$4,040.00** each
Qty 10-24	**A$3,636.00** each
Need More?	Request Quote

Product Downloads

General

Note:

Included Accessories:
SMA Adapters: #89-643 (x2)
Port Plugs: #89-644 (x1) and #89-645 (x1)

Physical & Mechanical Properties

Diameter (inches):

2

Diameter of 0° Port (inches):

1.00

Diameter of Port 2 (inches):
0.50

Diameter of Port 3 (inches):
0.50

Diameter of Port Plugs (inches):
1.00 & 0.50

Diameter of SMA Adapter (inches):
0.50

Dimensions (inches):
2.61 x 2.61 x 2.61 (Cubic Outer Shape)

Optical Properties

Coating:
Spectralon®

Damage Threshold, By Design:
8 J/cm^2

Threading & Mounting

Mounting Threads:
¼-20

Environmental & Durability Factors

Thermal Stability:
Up to 350°C

Regulatory Compliance

RoHS 2015:
Compliant

Reach 209:
Compliant

Certificate of Conformance:
View

Product Details

- Ideal for Measuring Light Sources
- Can be Upgraded to Calibrate Sensors and Test Lenses
- Designed for Simple System Integration

General Purpose Integrating Sphere Systems are designed to spatially integrate radiant flux in order to measure optical radiation. The spheres can be coupled with a sensor to create radiometers, photometers, or spectroradiometers in order to measure the total geometric flux emanating from a light source or the flux density of an illuminated area. Additionally, these sphere systems can be used to measure the output of high power lasers and laser diodes or to measure the reflectance and transmittance of materials.

A variety of accessories are available for modifying or upgrading the performance of the systems, including port plugs, port reducers, and uniform source lamps. Uniform source lamps are ideal for many irradiance applications, such as characterizing the responsivity, linearity, photo response non-uniformity, and dynamic range of focal-plan arrays. Additionally, these sources can be used for evenly illuminating test targets for evaluating the CTF of optical systems or imaging lenses, and for measuring cosine^4 irradiance falloff or other variations in irradiance within optical systems caused by optical aberrations.

;